Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/672,990	LEE, JAE JIN	
Examiner	Art Unit	
Linh M. Nguyen	2816	

	SEARCHED				
Class	Subclass	Date	Examiner		
327	26	03/17/05	und		
327	26 36	"	V		
4	31 14g	Ч	ų		
4	149	4	4		
4	153	4	y		
и	158	ų	ų		
"	158 161	4	ų		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
327	158	03/17/05	LAN	
	31			
_				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
·		